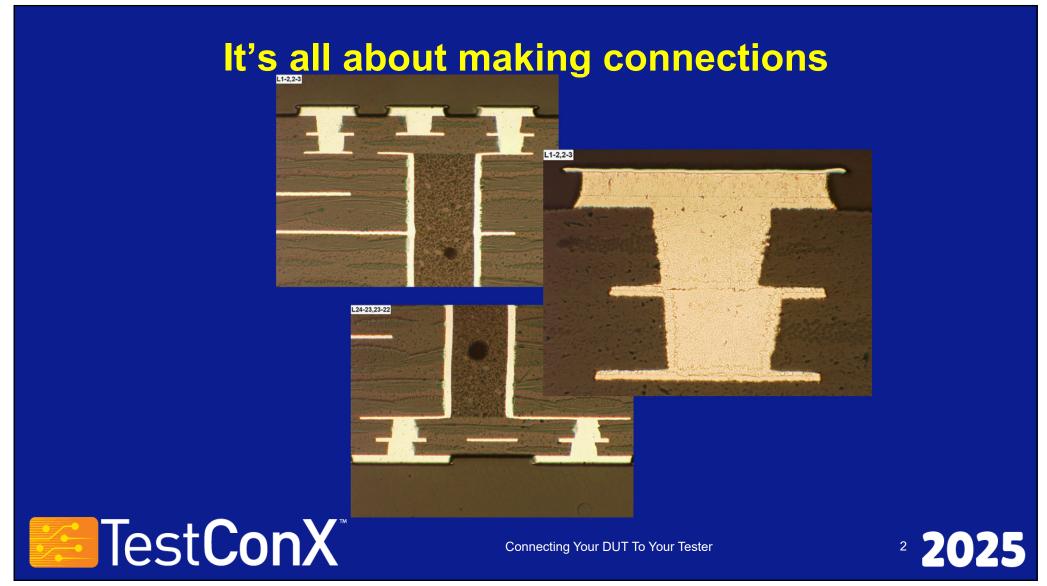
Connecting Your DUT To Your Tester

Tom Bresnan R&D Altanova / Advantest Group

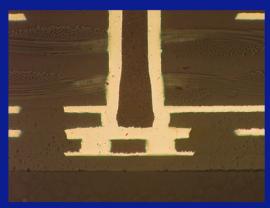


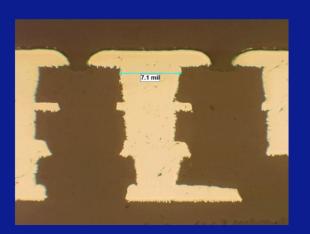




It's all about making (good) connections







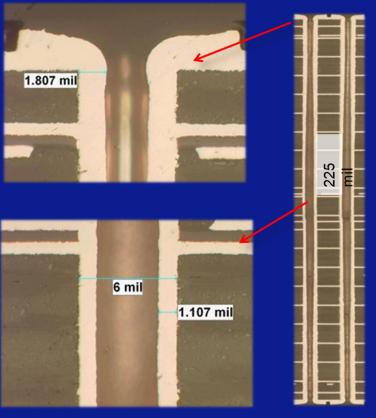


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TestConX

It's all about making (good) connections

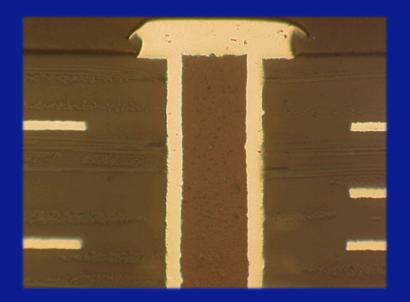




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It's all about making (good) connections





Connecting Your DUT To Your Tester

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Why Are We Here?

- What is it?
 - How PWB's relate to ATE
 - Printed Wiring Boards Automated Test Environment
 - Some Attributes
- Materials
- Let's take a break!
- Process flow and "How's it made?"
 - Including some videos of major processes



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What's in a Name?

- PWB's
- PCB's
 - Printed Circuits Board
- DUT board, DIB, PIB, load board,

or ATE board

- Device Interface Board (DIB)
- Probe Interface Board (PIB)
- Interface Board
 - Between the <u>Device Under Test and the Tester</u>



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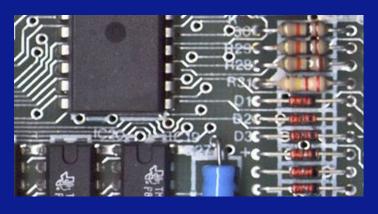
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What Is It?

Wikipedia

A printed wiring board (PWB) mechanically supports and electrically connects electronic components using conductive tracks, pads and other features etched from copper sheets laminated onto a non-conductive substrate. PWBs can be single sided (one copper layer), double sided (two copper layers) or multi-layer (outer and inner layers). Multi-layer PWBs allow for much higher component density. Conductors on different layers are connected with plated-through holes called vias. Advanced PWBs may contain components - capacitors, resistors or active devices embedded in the substrate.



1980's PWB technology

"PCB Spectrum" by Bill Bertram - Bill Bertram. Licensed under CC BY-SA 3.0 via Commons -



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What Is It?

- Simultaneously, a PWB is:
 - Mechanical Device
 - Electrical Device
 - Thermal Device



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PWB Classifications

- There are two basic ways to form circuits on a PWB
- Additive
 - Formation is accomplished by adding copper to a bare PWB, then etching the pattern intended (through ~ 2 oz copper)
- Semi-Additive
 - Imaging and plating on top of base copper foil and the unwanted portion of that copper foil is etched away, leaving the desired pattern
 - Our discussion today will focus on processes related to the latter method



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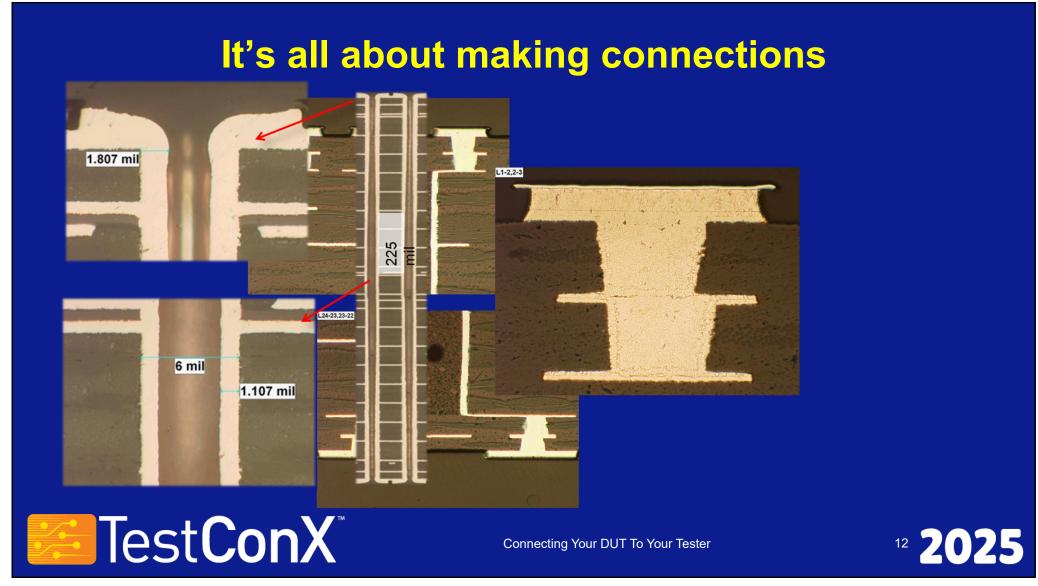
PWB Classifications

- Single-sided
 - Circuitry on one side only, components installed on back side
- Double-sided
 - Circuitry on both sides, plated thru holes, components on one or both sides
- Multilayer
 - To increase area for routing, multiple layers may be inside
 - Through holes, buried via's or blind via's may be employed to further increase circuit layout density



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The Marketplace

- Worldwide Market 2024
 - \$70B
 - Estimated to grow to \$90B by 2029
- North American Market 2023
 - -~\$12B \$15B
- ATE
 - \$1.5B to \$2.5B
 - Difficult to estimate



Today's Modern Load Board



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Measuring Units Used in PWB Industry

Units	Micro Inches	Microns	Mils	MM	Inches	Angstroms
Micro Inch	1	0.025	0.001	0.000025	0.000001	250
Micron	40	1	0.04	0.001	0.00004	10,000
Mil	1000	25	1	.025	0.001	250,000
MM	40,000	1,000	40	1	0.04	100,000,000



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Attributes of A PWB & Difficulty Levels

Attribute	Туре	Low	Medium	High	ATE
Layer Count		2-40	40 to 60	60+	68+
Board Thickness		3.2mm	5.1mm	6.35mm	8.0mm+
Aspect Ratio	Plated Thru Hole	12:1	15:1	20:1	30+:1
	Blind Via	2:1	1:1	0.75:1	
Line & Space	Inner Layer	100μ/100μ	75µ/75µ	50μ/50μ	50µ/50µ
	Outer Layer	125μ/125μ	75µ/75µ	50μ/75μ	50µ/50µ
Minimum Drill		250µ	200µ	150µ	100µ
Solder Mask Registration		100μ	75µ	50µ	



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Attributes of A PWB (in inches)

Attribute	Туре	Low	Medium	High	ATE
Layer Count		2-40	40 to 60	60+	68+
Board Thickness		0.126	0.200	0.250	0.320+
Aspect Ratio	Plated Thru Hole	12:1	15:1	20:1	30+:1
	Blind Via	2:1	1:1	0.75:1	n/a
Line & Space	Inner Layer	0.004/0.004	0.003/0.003	0.002/0.002	0.002/0.002
	Outer Layer	0.005/0.005	0.003/0.003	0.002/0.003	0.002/0.002
Minimum Drill		0.010	0.008	0.006	0.004
Solder Mask Registration		0.004	0.003	0.002	



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Attributes of a Device

- Pitch
 - Device, trace, space, hole to copper
- Layers
 - Rows on a BGA device
- Hole Diameter
 - Function of device pitch
- Aspect Ratio
 - Ratio of thickness to hole diameter (think soda straw)



Photo credit: 1stretroshop.com



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Attributes – By Device Pitch

- 1.0mm, 0.8mm, 0.5mm, 0.4mm
- Translates to other attributes
 - Line width
 - Spacing
 - Dielectric spacing
 - Hole to copper feature dimensions



To Your Tester 18 **2025**

Attributes by Device Pitch

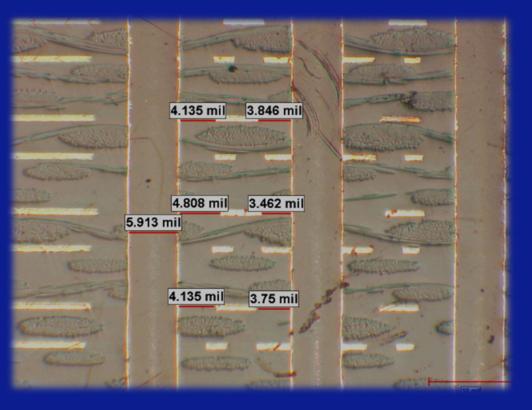
	1.0mm (0.0394)	0.8mm (0.0315)	0.5mm (0.0197)	0.4 mm (0.0157)
Pad	0.76mm (0.0299)	0.66mm (0.026)	0.35mm (0.0138)	0.3mm (0.0118)
Hole	0.37mm (0.0146)	0.3mm (0.0118)	0.15mm (0.0059)	0.1mm (0.0039)
Line	200µ (0.008)	200µ/125µ (0.008/0.005)	200µ/75µ (0.008/0.003)	200µ/50µ 0.008/0.002)
Hole 2 Copper	0.25mm (0.010)	0.18mm (0.007)	0.12mm (0.005)	0.1mm (0.004)
Aspect Ratio	Low	Medium	High	Extreme



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Hole to Copper Dimensions





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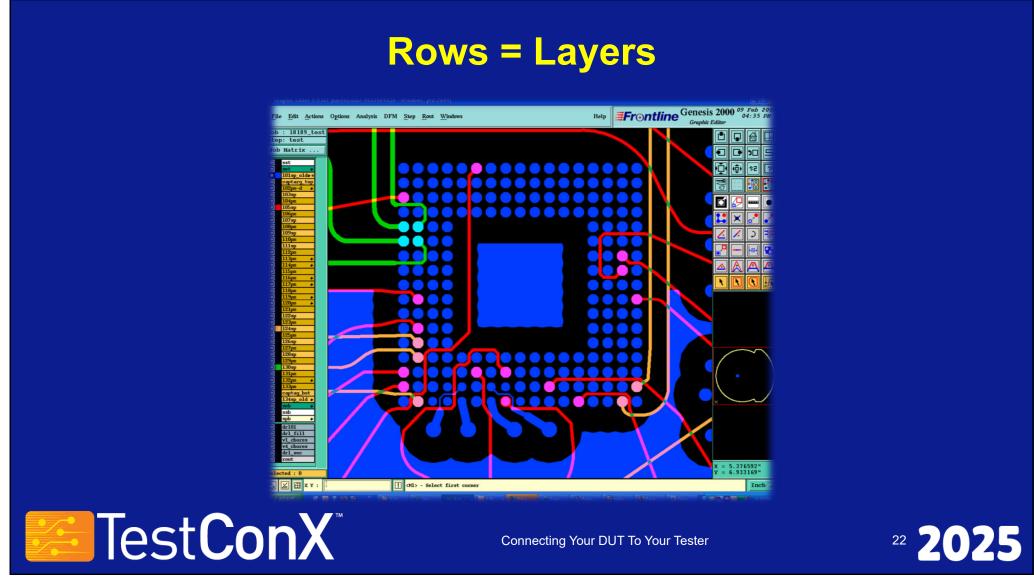
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Attributes - Layers

- Each row of a BGA device = one signal layer
- Signal layers need corresponding ground planes
 - Impedance control
- May need additional routing layers



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Attributes – Hole Diameter

- Drilled or finished hole diameter
- Human Hair
 - -40μ to 250 μ (0.0015" to 0.010")
 - -100μ is pretty average (0.004")
- Today's interface boards are drilled with a 100µ to 150µ drill bit (0.004" to 0.006")
 - And smaller



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Attributes – Aspect Ratio

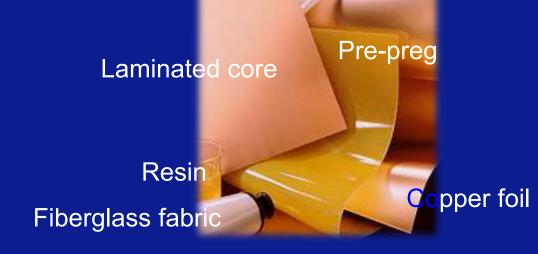
- Ratio of the board thickness relative to drilled hole diameter
- 1.0mm device, 13:1
- 0.8mm device, 16:1
- 0.5mm device, 31:1
- 0.4mm device, 38:1
- 0.35mm device, >40:1



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Let's Talk About Materials

 Wikipedia...A printed circuit board, or PCB, is used to mechanically support and electrically connect electronic components using conductive pathways, on a nonconductive substrate.





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Photo courtesy of Isola

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Materials & More

Material properties are playing an increasingly important role in advanced board designs as speed, power dissipation, signal fidelity and process temperatures increase

Factors that influence material selection

Electrical Design:
Dielectric constant
Loss tangent

Reliability: Assembly process Long-term life Thermal/Mechanical: X, Y, Z CTE Conductive cooling



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Laminates

- Pre-preg
 - Fiberglass cloth (woven)
 - Resin
- Copper foil
 - Electrodeposited (ED)





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Photo courtesy of Isola

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Why Copper?

- Copper is an excellent electrical conductor
- Low electrical resistivity
- Inexpensive metal
- Soft and easily workable
- Easily processed
- Patternable by photolithography
 - Using relatively benign chemistry



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Copper Foil

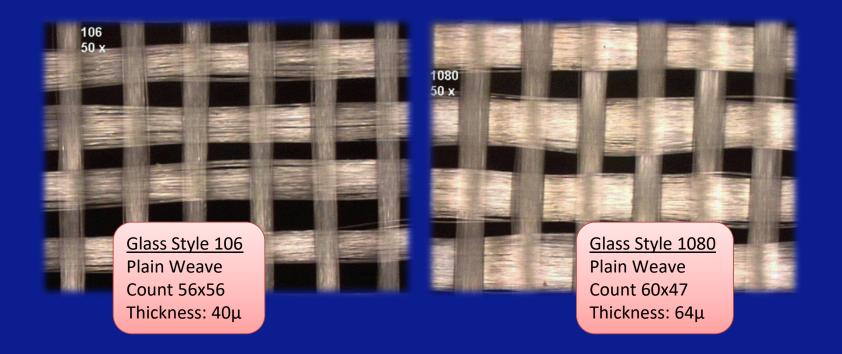
- Copper is the dominant metal for interconnection use
- Specified by weight
 - $-\frac{1}{2}$ ounce per square foot
 - 1 ounce per square foot
- Corresponding thicknesses
 - 17u and 35u respectively
- Usually produced by electrolytic deposition on a mandril
 - 99.8% purity common
 - Thickness tolerance is approx. 10%



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Materials – 'Pre-Preg'



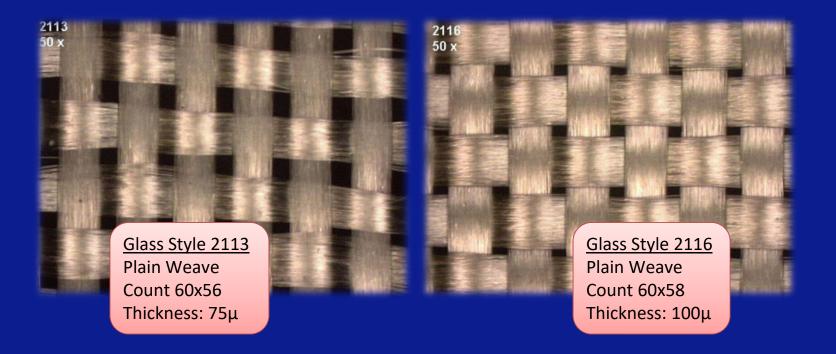


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Photos courtesy of Isola

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Materials - 'Pre-Preg'



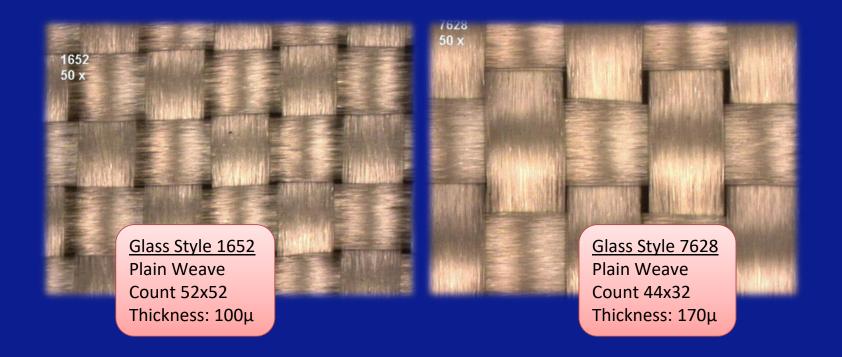


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Photos courtesy of Isola

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Materials - 'Pre-Preg'





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Laminate

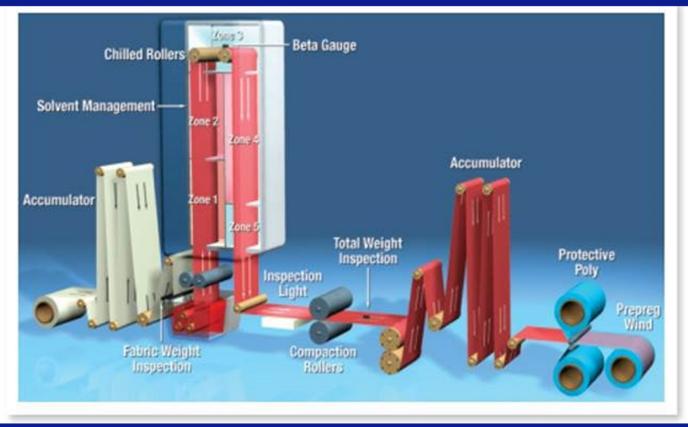
- Enhanced FR-4's
- Modified Epoxies
- Teflon
- BT
- Polyimide
- Hybrid
- Too many to do justice to each supplier



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Pre-Preg - how it's made

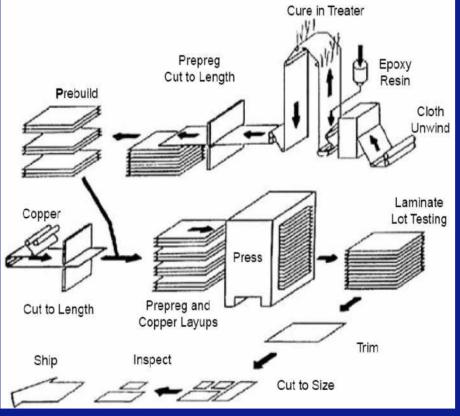




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Laminate Process Flow





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Laminate – How It's Made



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Laminate – How It's Made





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Laminate Construction (caveat emptor)

Thickness	Tolerance	Construction	Resin Content	E _r @ 1 MHz	E _r @ 10 GHz	
0.008	0.001	1x 7628	44.4%	4.55	4.12	
0.008	0.001	2x 2116	43.0%	4.54	4.11	
0.008	0.001	1x 2116 1x 2113	48.6%	4.36	4.02	
0.008	0.001	1x 7629	42.6%	4.38	4.12	



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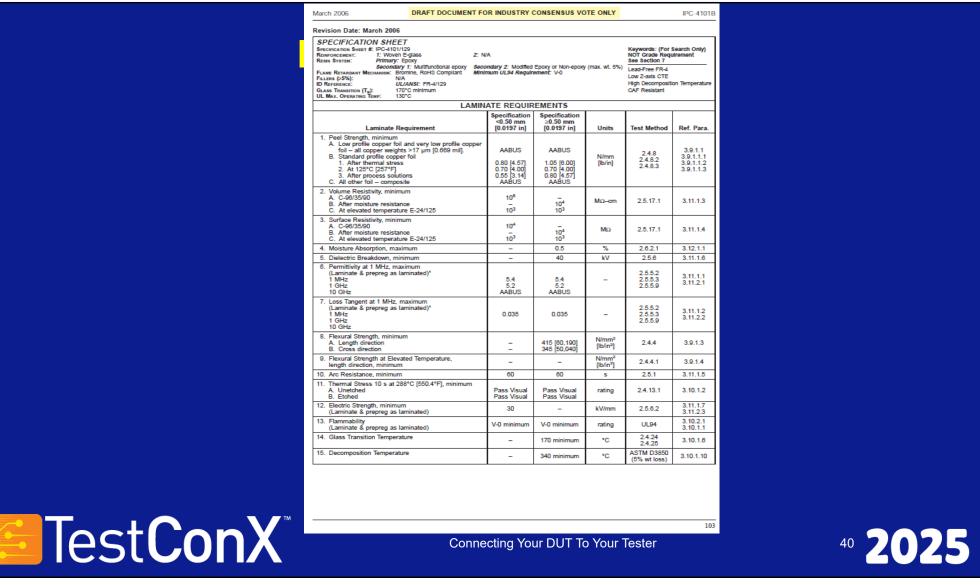
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Laminate Construction

- Know what you're getting
- Understand the implications
- Electrically significant or not
- Mechanically significant!



Connecting Your DUT To Your Tester



Material Properties

- Mechanical and Thermal
 - Peel strength
 - X-Y CTE
 - Z CTE
- Tg
 - DSC
 - TMA
 - DMA



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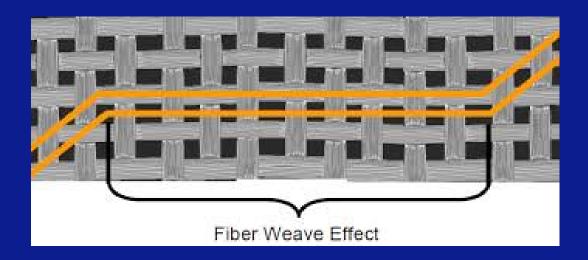
Material Properties

- Electrical
 - Dielectric Constant or
- ε_r Epsilon-sub-r (or relative permittivity)
 - The dielectric constant is a ratio of the capacitance of a capacitor in which a particular insulating material is the dielectric, to the capacitance of the capacitor in which a vacuum is the dielectric.
 - Also known as E-sub-r
- Effective Permittivity



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Material Properties – Weave Effect

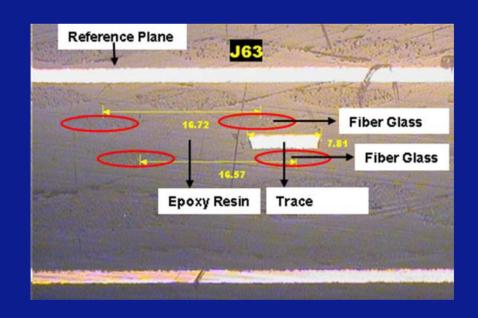


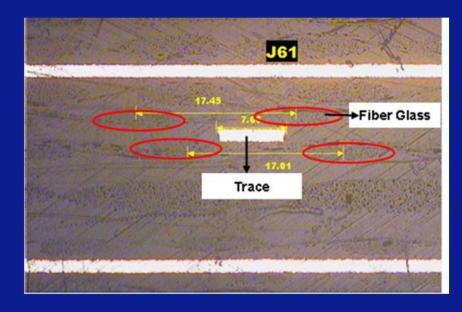


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Material Properties – Weave Effect

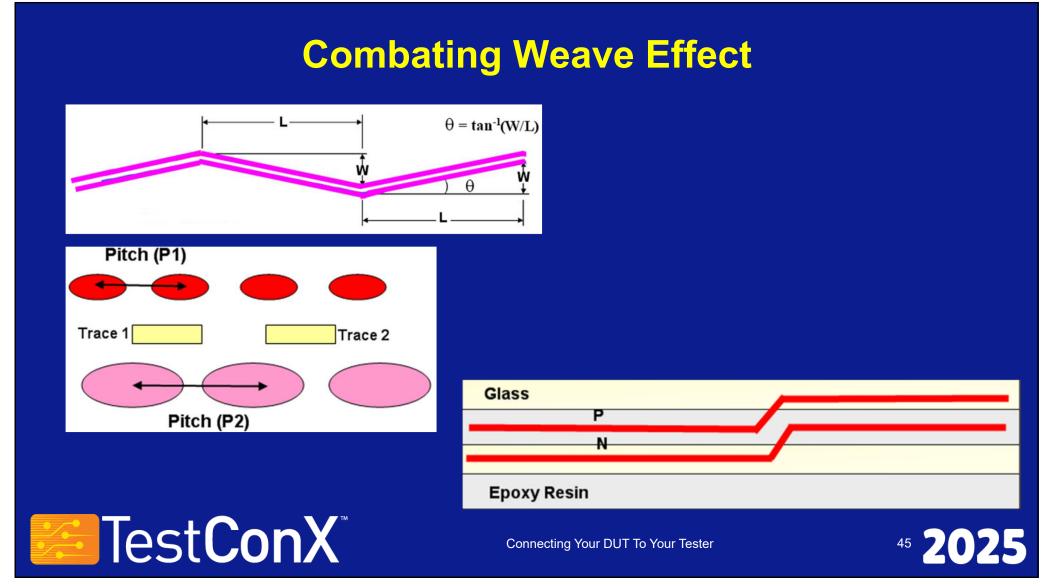






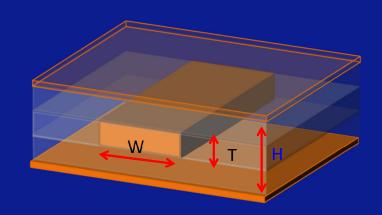
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Material Properties – Trace Variabilities

- Dry film etch tolerance is +/-12µ;
 therefore as W decreases Z0 error increases.
- As H decreases, tolerance changes from +/- 10% to ~+/-15μ. H also varies within a sheet +/- 10μ.
- T does not vary significantly, but a 'tall' T results in higher resin flow around the trace and makes the final thickness H somewhat less predictable.
- A 'tall' T is also prone to under etch, which influences Z0.



• Fiberglass reinforced materials are not homogenous, and ϵ_r is not constant in the material.

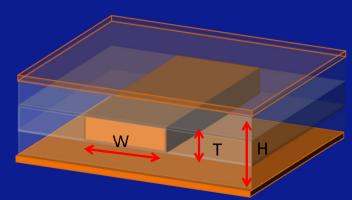
*Z0 or Z naught = impedance



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Material Properties – Trace Variabilities



• Important: driven by etch variation and by heterogeneous materials Z0 varies as a function of distance.

100um example in 1/2 Oz copper:								
Trace Etch Width								
	min	nominal	max					
	88 um	100 um	112 um					
	53.2 Ω	50.1 Ω	47.4 Ω					
Height	Height							
	min	nominal	max					
	201 um	223 um	245 um					
	47.0 Ω	50.1 Ω	53.0 Ω					
Combined Error								
	min	nominal	max					
	44.3 Ω	50.1 Ω	56.1 Ω					



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	Materials Chart											
	Mwave 1000	Mwave 2000	Mwave 3000	Mwave 4000	Meg 6	Rogers 4350	N4000- 13	N4000- 13SI	N4800- 20	N4800- 20SI	Astra MT7	Tachyon 100
Mech												
Peel strength												
After float	6.6	6.6	5.5	5.5	.8kN/m	5	7.5	7.5	7	7	5.7	
At elev. temp	5.6	5.6	4.4	4.4	n.a.	n.a.	8.1	8.1	6.5	6.5	n.a.	5.5
After exp./proc	5.3	5.3	5	5	n.a.	n.a.	9	9	7	7	n.a.	5.5
X-Y CTE	10-14	10-14	10-14	10-14	14-16	10-12	10-14	10-14	10-14	10-14	12	15
Z CTE α1	55	55	55	55	45	32	70	70	27	31	60	45
Z CTE α2	260	260	260	260	260	n.a.	280	280	205	210	300	250

α1, 50C to Tg; α2, Tg to 260C



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Materials Chart Mwave Meg 6 N4000 N4000 N4800 N4800 Mwave Mwave Mwave Rogers **Astra Tachyon** 1000 2000 3000 4000 -13 **-13SI** -20 -20SI MT7 4350 100 **Electrical** Dk 2 Ghz 3.7 3.7 3.2 3.7 3.4 3.8 3.5 3.71 3.55 3 3.04 n.a. 10 Ghz 3.7 3.4 3.8 3.5 3.61 3.48 3.7 3.3 3.8 3.4 3 3.02 Df 2 Ghz 0.003 0.0032 0.002 0.002 0.0031 0.009 0.008 0.007 0.0055 0.0017 0.004 0.0021 10 Ghz 0.0048 0.0075 0.0017 0.0055 0.004 0.0028 0.004 0.0037 0.008 0.007 0.006 0.0021 **Thermal** (Tg) **TMA** 215 215 170 170 280 200 200 180 180 180 n.a. n.a. DMA 240 240 240 210 210 220 200 200 210 n.a. 240 n.a. DSC 185 210 210 200 200 200 185 n.a. n.a. n.a. n.a. n.a.

DSC, Differential Scanning Calorimetry; TMA, Thermomechanical Analysis; DMA, Dynamic Mechanical Analysis.



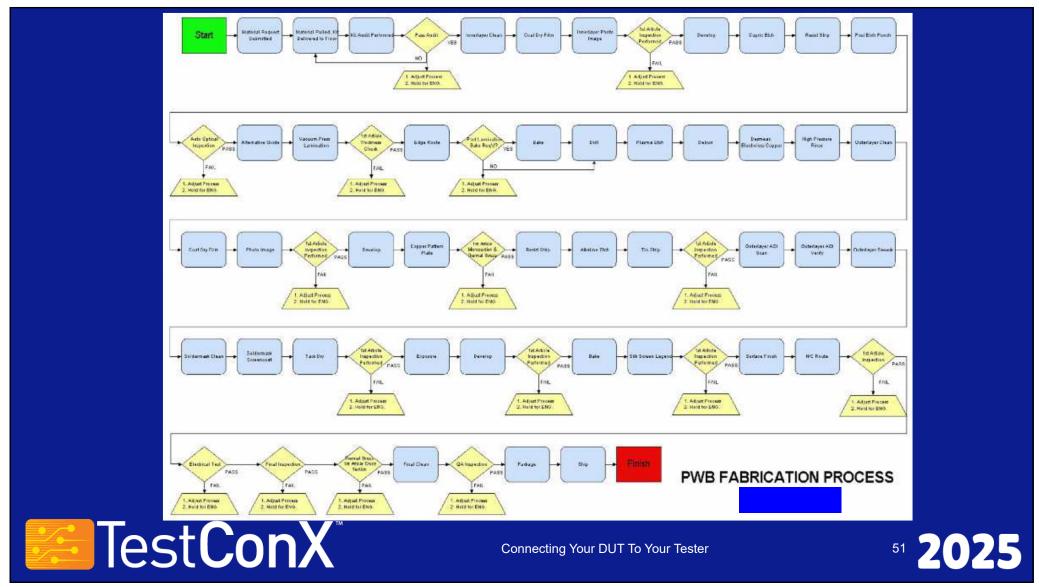
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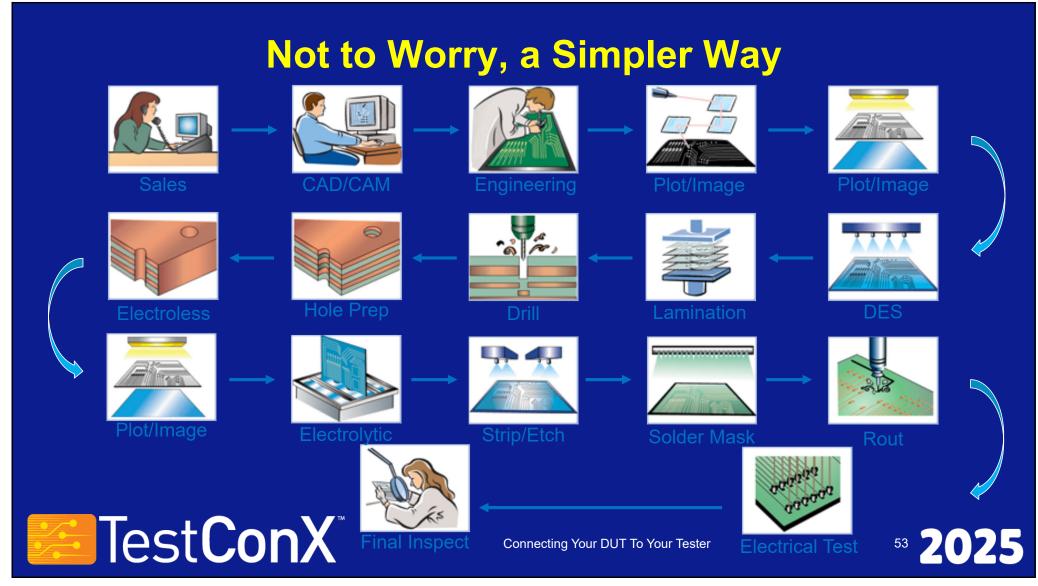
Before We Continue to The Process

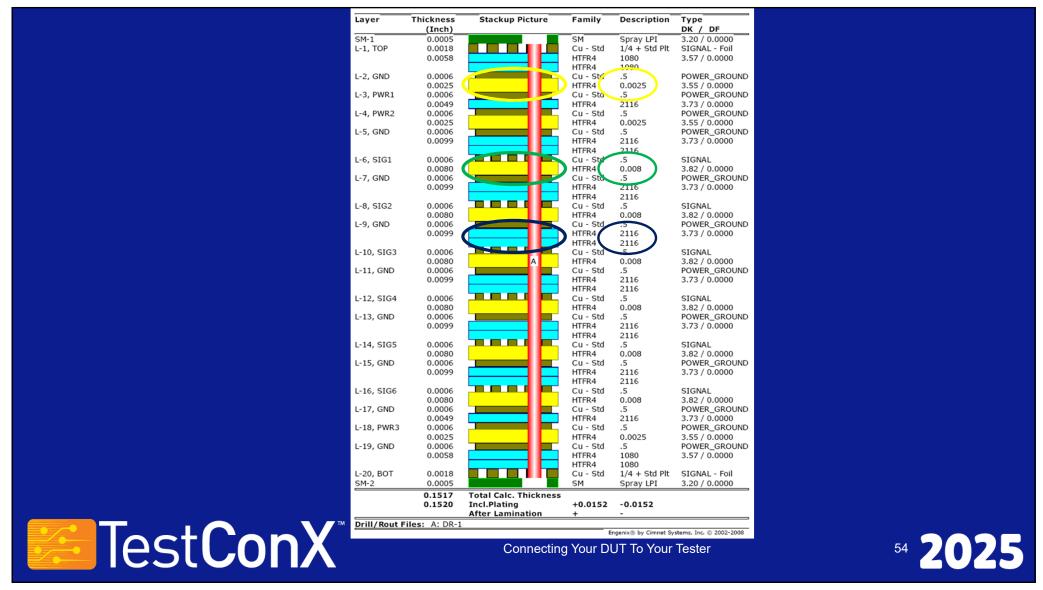


Connecting Your DUT To Your Tester









The Process – Inner Layer Imaging

- Photo resist application
- UV Exposure
 - Laser Direct Imaging (LDI)
 - Collimated light & film
 - Polymerizes resist
- Develop
 - Removes non-polymerized resist





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The Process – Inner Layer Imaging

- Photo resist application
- UV Exposure
 - Laser Direct Imaging (LDI)
 - Collimated light & film
 - Polymerizes resist
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The Process – Inner Layer Imaging

- Photo resist application
- UV Exposure
 - Laser Direct Imaging (LDI)
 - Collimated light & film
 - Polymerizes resist



Removes non-polymerized resist





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The Process – Inner Layer Imaging

- Etch & Strip
- Removal of base copper
 - Non-polymerized area
- Various chemistries available
 - Ammonia based
 - Cupric chloride based
- Resist removal



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The Process – Automatic Optical Inspection

Post-Etch Punch

- Registers all layers to common optical targets
- Slots added for tooling purposes

AOI

- Data downloaded from CAM
- Core layer scanned
- Compared to CAM data
- Verification





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The Process – Oxide Treatment

- Copper Surface Preparation
 - Adhesion promotion
 - Added bonding strength
 - Reduced oxide
 - Pink ring elimination
 - Alternative oxide
 - Variety of materials
 - Multiple or sequential laminations



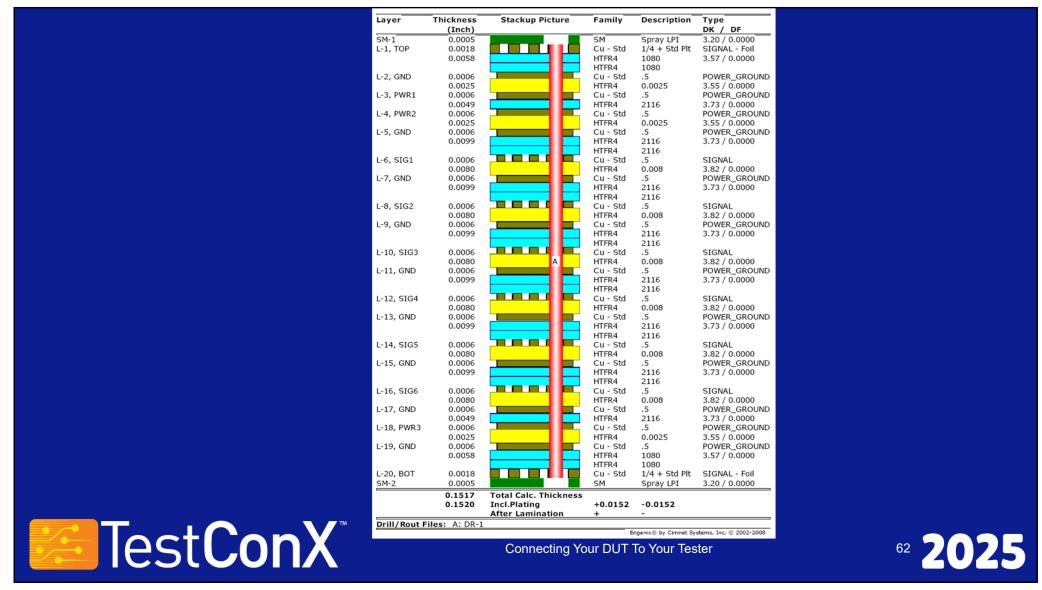
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The Process – Layup & Lamination

- Registration and stacking of cores
 - Process combines cores, pre-preg and copper foil
 - Multiple times thru this process may be required
 - Simple thru-hole vs. sequential lamination
- Pin lamination
 - Registration or layer to layer alignment
- Vacuum chamber
- Heat, pressure, time
- Tightly controlled process window



Connecting Your DUT To Your Tester



The Process - Drill

- Mechanical hole formation
 - $-100\mu 150\mu$ typical
- Opto-mechanical positioning
 - Glass scales
- Real-time drill bit analysis
 - Diameter
 - Run-out
 - Broken bit detection
- Stub drilling or back drilling





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The Process - Drill

- Laser hole formation
 - Microvias down to 25µ
- Opto-mechanical positioning
 - Blind vias
 - Buried vias

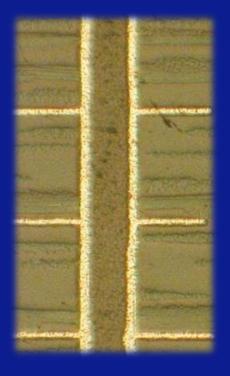


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The Process – Hole Prep & Copper Plate

- Desmear
 - Removes epoxy smear from interconnects
 - Created during drill operations
 - Chemical removal

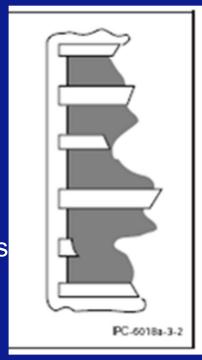




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The Process – Hole Prep & Copper Plate

- Etchback
 - Different from desmear
 - Removes epoxy resin from dielectric space
 - May include a glass etch
 - Three point connection
 - Some materials resistant to previous chemical process





Connecting Your DUT To Your Tester

The Process – Hole Prep & Copper Plate

- Electroless copper deposition
- Seed layer
 - Prepares dielectric and interconnects for subsequent plating operations
 - 30 micro-inches 40 micro-inches followed by copper plating
 - 75 micro-inches 125 micro-inches to prep for imaging process
- Unfriendly chemistry
- Inherently unstable



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The Process – Hole Prep & Copper Plate

- Carbon
- Graphite
- Palladium
- Electroless Nickel
- Conductive Polymer
- Non-Formaldehyde-Based Electroless Copper



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The Process – Hole Fill

- Fill to create flat surface
 - Needed for socket touchdown
- Vacuum assist
- High aspect ratio
- Blind vias







Connecting Your DUT To Your Tester

The Process - Planarization

- Fill to create flat surface
 - Needed for socket touchdown
- Vacuum assist
- High aspect ratio
- Blind vias
- Planarize the surface





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The Process – Outer Layer Imaging

- Reversed from inner layer imaging
- Plating resist, not etch resist
- Photo-resist application
- UV Exposure
 - Film and collimated light
 - LDI or Laser Direct Imaging
 - Polymerizes photo-resist
- Develop
 - Removal of non-polymerized resist



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The Process – Copper-Nickel-Gold Plating

- Electroplating
 - Chemistry (electrolyte solution)
 - Power rectifier
 - Rectifier converts AC to DC
 - Anode (copper)
 - Cathode (PWB panel)





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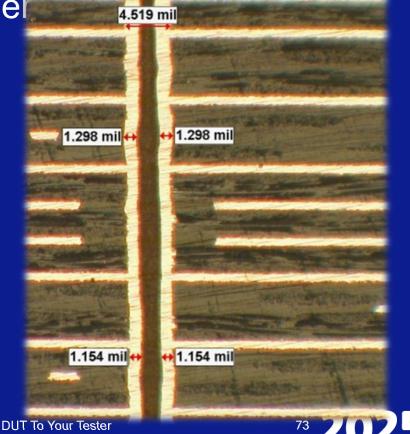
TestConX 2025 **Tutorial 2**

The Process – Copper-Nickel-Gold Plating

 1 mil (25 micron) minimum copper thickness in holes

Minimize surface buildup

- Aspect ratio
 - Through holes or microvias
- Robust and survivable
- Etch resist





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The Process – Outer Layer Etch

- Define the outer layer(s) pattern
 - Removal of base copper
 - Defines lines, pads, other features
 - Impedance control
- Nickel / Hard Gold typical ATE finish
- Etch factors and 'overhang'
- Other finishes available





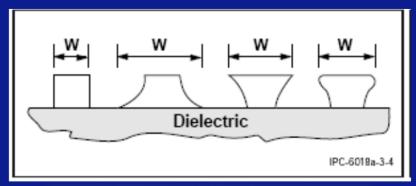
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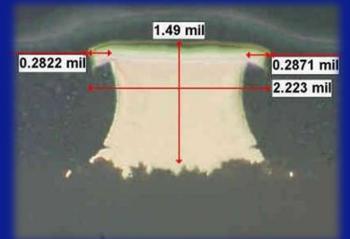
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The Process – Outer Layer Etch

- Overhang
 - Depends on surface finish
 - 1:1 thickness
 - Surface thickness critical







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The Process – Electrical Test

- Direct measurement for first board
 - Indirect measurement of subsequent boards
- Isolation and continuity
- Capacitive or electromagnetic coupling
 - Broken traces = reduced coupling
 - Shorted traces = increased coupling
- Trace to ground (increased degree of confidence)
- Adjacency analysis





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The Process – Solder Mask

- Epoxy based coating
 - Available in colors and clear
- Surface protection
- Solder resist, as the name implies
- Product identification
- Liquid Photo-imageable
 - Spray coated or screen flood
- Dry film still in use



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The Process – Silk Screen or Legend

- Assembly nomenclature or legend
- Available colors
- Product identification
- Screen print
- Inkjet



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The Process - Depanelization

- Secondary Drill (non-plated holes)
- Back drill or stub drill
- Counterbores / countersinks
- Slots
- Routing





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The Process – Final Inspection

- Visual and dimensional
- Cosmetic defects
- Impedance testing
- Cross sections
- Other measurements and certifications



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May this information help you weather your PWB storms



https://www.pinterest.com/source/ anchorcharters.com.au/

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About Us – R&D Altanova

- Founded in 1969
- Part of the Advantest Group AAI since 2021
- Full Turn-Key Supplier
 - SI/PI Engineering
 - Mechanical Engineering
 - Design & Layout
 - Fabrication (US & Taiwan)
 - Assembly
 - Sockets and Interconnects spring probe & elastomer



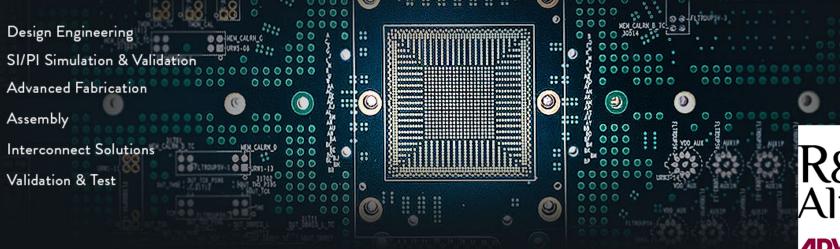
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Thank You!

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Visit our website – www.rdaltanova.com

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